

MODULE SCREENING TEST PLAN For Module H1

TEST	CONDITION	MIL-STD-750 TEST METHOD
Group A	Reverse Current (I_R) @ rated V_{WM} Breakdown Voltage ($V_{(BR)}$) @ I_T Clamping Voltage (V_C) @ I_{pp} , t_p = Rated Forward Voltage (V_F) @ I_F , t_p = 8.3ms	4016 4022 4011